

Atty Docket No. 019916-003810US

PTO FAX NO.: 703-872-9306

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Group Art Unit 1655

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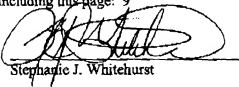
I hereby certify that the following documents in re Application of Stephen A. Empedocles, et al., Application No. 09/882,193, filed June 13, 2001 for SINGLE TARGET COUNTING ASSAYS USING SEMICONDUCTOR NANOCRYSTALS is being facsimile transmitted to the Patent and Trademark Office on the date shown below.

Document(s) Attached

1. Response to Bona Fide Attempt Letter

Number of pages being transmitted, including this page: 9

Dated: November 19, 2003


Stephanie J. Whitehurst

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By: Suzanne J. Whitburn

PATENT
Attorney Docket No.: 019916-003810US
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Stephen A. Empedocles, *et al.*

Application No.: 09/882,193

Filed: June 13, 2001

For: SINGLE TARGET COUNTING
ASSAYS USING SEMICONDUCTOR
NANOCRYSTALS

Customer No.: 20350

Confirmation No.: 9111

Examiner: Betty J. Forman

Technology Center/Art Unit: 1634

RESPONSE TO BONA FIDE ATTEMPT
LETTER

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Bona Fide Attempt Letter mailed October 24, 2003, please enter the following amendments and remarks:

Claim Listing begins on page 2 of this paper.

Remarks/Arguments begin on page 8 of this paper.